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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	324
Number of Logic Elements/Cells	1296
Total RAM Bits	-
Number of I/O	133
Number of Gates	16000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc5210-6pq160c

The XC5200 CLB consists of four LCs, as shown in Figure 4. Each CLB has 20 independent inputs and 12 independent outputs. The top and bottom pairs of LCs can be configured to implement 5-input functions. The challenge of FPGA implementation software has always been to maximize the usage of logic resources. The XC5200 family addresses this issue by surrounding each CLB with two types of local interconnect — the Local Interconnect Matrix (LIM) and direct connects. These two interconnect resources, combined with the CLB, form the VersaBlock, represented in Figure 2.

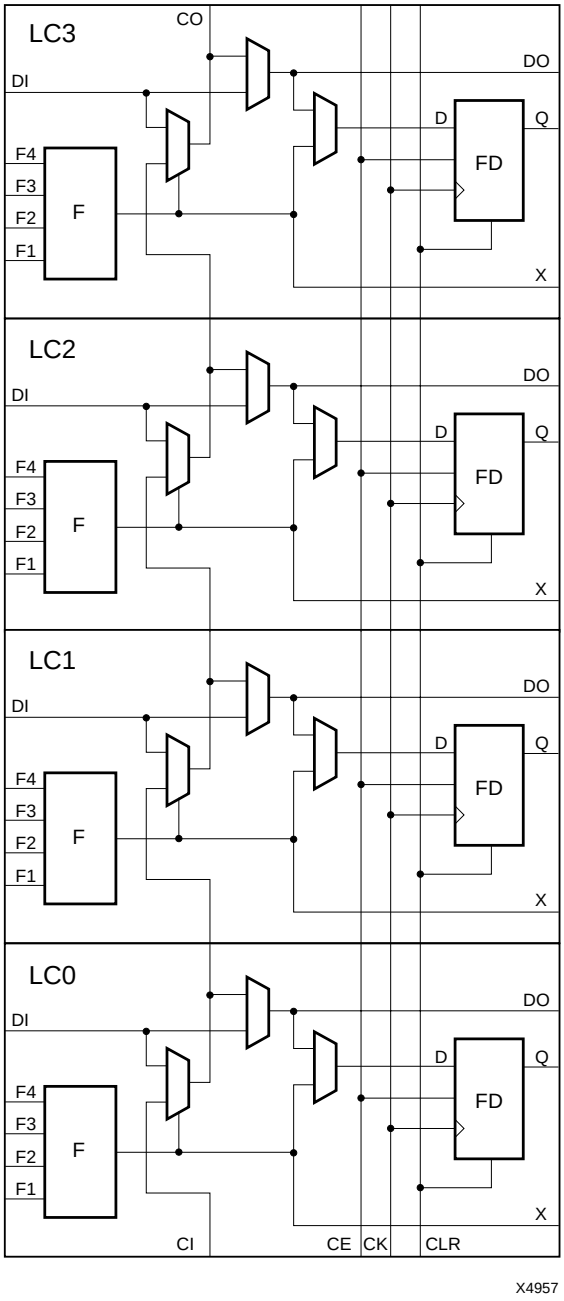

Figure 4: Configurable Logic Block

The LIM provides 100% connectivity of the inputs and outputs of each LC in a given CLB. The benefit of the LIM is that no general routing resources are required to connect feedback paths within a CLB. The LIM connects to the GRM via 24 bidirectional nodes.

The direct connects allow immediate connections to neighboring CLBs, once again without using any of the general interconnect. These two layers of local routing resource improve the granularity of the architecture, effectively making the XC5200 family a “sea of logic cells.” Each Versa-Block has four 3-state buffers that share a common enable line and directly drive horizontal and vertical Longlines, creating robust on-chip bussing capability. The VersaBlock allows fast, local implementation of logic functions, effectively implementing user designs in a hierarchical fashion. These resources also minimize local routing congestion and improve the efficiency of the general interconnect, which is used for connecting larger groups of logic. It is this combination of both fine-grain and coarse-grain architecture attributes that maximize logic utilization in the XC5200 family. This symmetrical structure takes full advantage of the third metal layer, freeing the placement software to pack user logic optimally with minimal routing restrictions.

VersaRing I/O Interface

The interface between the IOBs and core logic has been redesigned in the XC5200 family. The IOBs are completely decoupled from the core logic. The XC5200 IOBs contain dedicated boundary-scan logic for added board-level testability, but do not include input or output registers. This approach allows a maximum number of IOBs to be placed around the device, improving the I/O-to-gate ratio and decreasing the cost per I/O. A “freeway” of interconnect cells surrounding the device forms the VersaRing, which provides connections from the IOBs to the internal logic. These incremental routing resources provide abundant connections from each IOB to the nearest VersaBlock, in addition to Longline connections surrounding the device. The VersaRing eliminates the historic trade-off between high logic utilization and pin placement flexibility. These incremental edge resources give users increased flexibility in preassigning (i.e., locking) I/O pins before completing their logic designs. This ability accelerates time-to-market, since PCBs and other system components can be manufactured concurrent with the logic design.

General Routing Matrix

The GRM is functionally similar to the switch matrices found in other architectures, but it is novel in its tight coupling to the logic resources contained in the VersaBlocks. Advanced simulation tools were used during the development of the XC5200 architecture to determine the optimal level of routing resources required. The XC5200 family contains six levels of interconnect hierarchy — a series of

single-length lines, double-length lines, and Longlines all routed through the GRM. The direct connects, LIM, and logic-cell feedthrough are contained within each Versa-Block. Throughout the XC5200 interconnect, an efficient multiplexing scheme, in combination with three layer metal (TLM), was used to improve the overall efficiency of silicon usage.

Performance Overview

The XC5200 family has been benchmarked with many designs running synchronous clock rates beyond 66 MHz. The performance of any design depends on the circuit to be implemented, and the delay through the combinatorial and sequential logic elements, plus the delay in the interconnect routing. A rough estimate of timing can be made by assuming 3-6 ns per logic level, which includes direct-connect routing delays, depending on speed grade. More accurate estimations can be made using the information in the Switching Characteristic Guideline section.

Taking Advantage of Reconfiguration

FPGA devices can be reconfigured to change logic function while resident in the system. This capability gives the system designer a new degree of freedom not available with any other type of logic.

Hardware can be changed as easily as software. Design updates or modifications are easy, and can be made to products already in the field. An FPGA can even be reconfigured dynamically to perform different functions at different times.

Reconfigurable logic can be used to implement system self-diagnostics, create systems capable of being reconfigured for different environments or operations, or implement multi-purpose hardware for a given application. As an added benefit, using reconfigurable FPGA devices simplifies hardware design and debugging and shortens product time-to-market.

Detailed Functional Description

Configurable Logic Blocks (CLBs)

Figure 4 shows the logic in the XC5200 CLB, which consists of four Logic Cells (LC[3:0]). Each Logic Cell consists of an independent 4-input Lookup Table (LUT), and a D-Type flip-flop or latch with common clock, clock enable, and clear, but individually selectable clock polarity. Additional logic features provided in the CLB are:

- An independent 5-input LUT by combining two 4-input LUTs.
- High-speed carry propagate logic.
- High-speed pattern decoding.
- High-speed direct connection to flip-flop D-inputs.
- Individual selection of either a transparent, level-sensitive latch or a D flip-flop.
- Four 3-state buffers with a shared Output Enable.

5-Input Functions

Figure 5 illustrates how the outputs from the LUTs from LC0 and LC1 can be combined with a 2:1 multiplexer (F5_MUX) to provide a 5-input function. The outputs from the LUTs of LC2 and LC3 can be similarly combined.

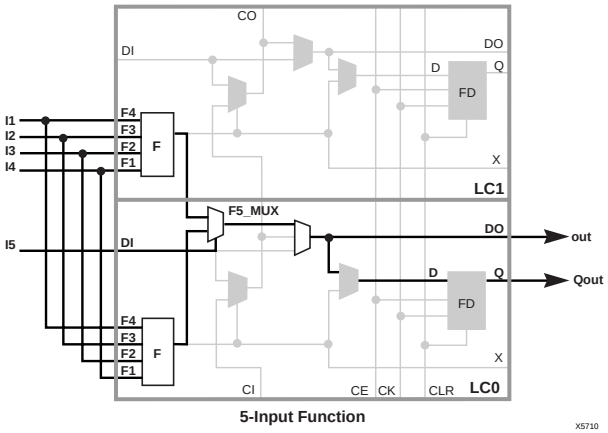

Figure 5: Two LUTs in Parallel Combined to Create a 5-input Function

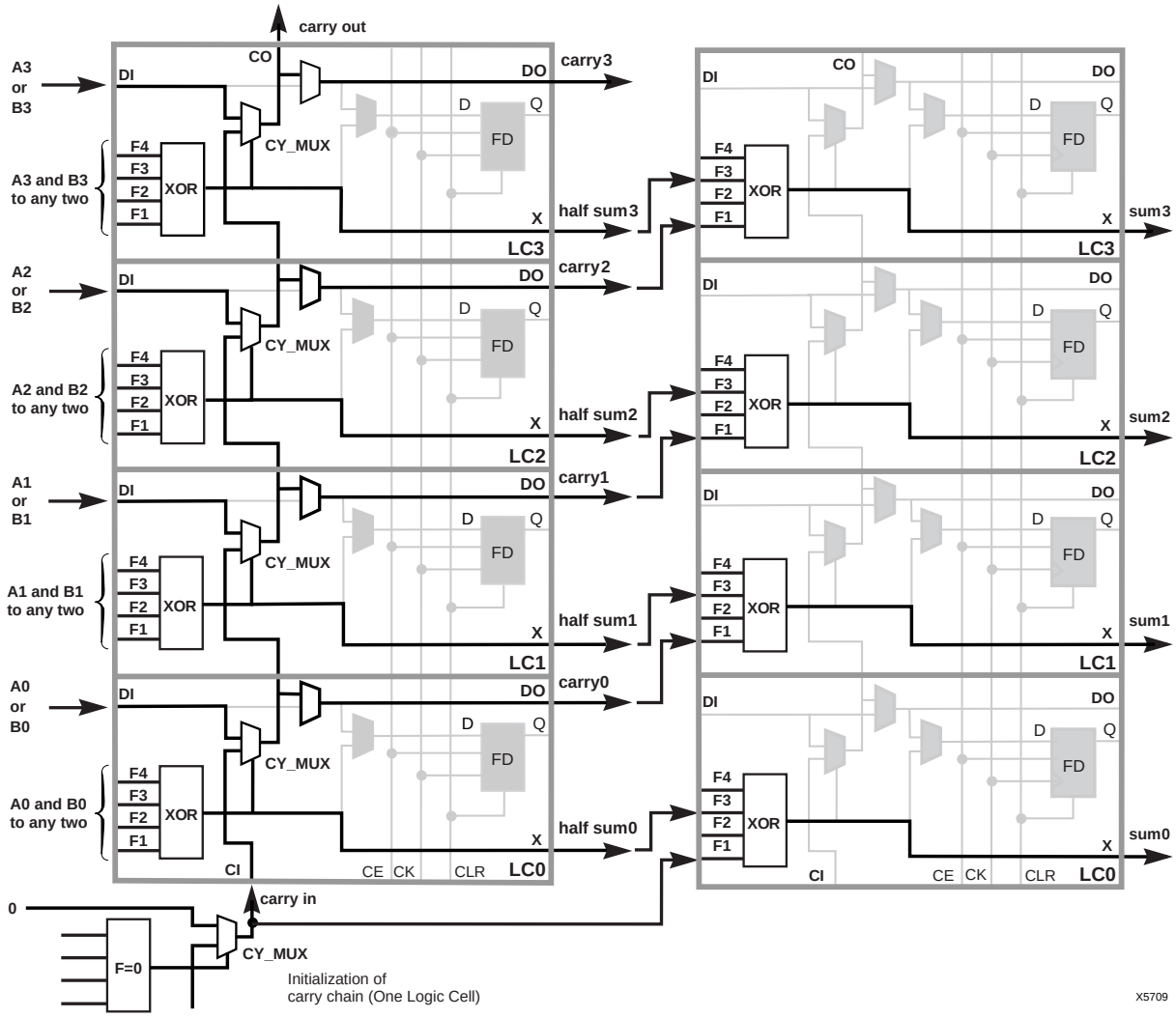

Figure 6: XC5200 CY_MUX Used for Adder Carry Propagate

Carry Function

The XC5200 family supports a carry-logic feature that enhances the performance of arithmetic functions such as counters, adders, etc. A carry multiplexer (CY_MUX) symbol is used to indicate the XC5200 carry logic. This symbol represents the dedicated 2:1 multiplexer in each LC that performs the one-bit high-speed carry propagate per logic cell (four bits per CLB).

While the carry propagate is performed inside the LC, an adjacent LC must be used to complete the arithmetic function. Figure 6 represents an example of an adder function. The carry propagate is performed on the CLB shown, which also generates the half-sum for the four-bit adder. An adjacent CLB is responsible for XORing the half-sum with the corresponding carry-out. Thus an adder or counter requires two LCs per bit. Notice that the carry chain requires an initialization stage, which the XC5200 family accomplishes using the carry initialize (CY_INIT) macro and one additional LC. The carry chain can propagate vertically up a column of CLBs.

The XC5200 library contains a set of Relationally-Placed Macros (RPMs) and arithmetic functions designed to take advantage of the dedicated carry logic. Using and modifying these macros makes it much easier to implement cus-

tomized RPMs, freeing the designer from the need to become an expert on architectures.

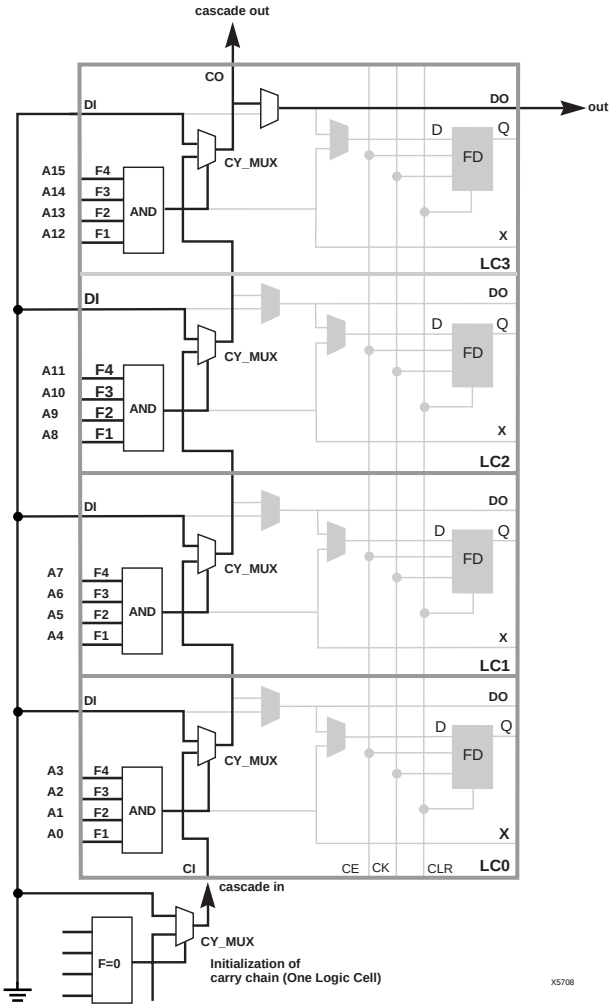

Figure 7: XC5200 CY_MUX Used for Decoder Cascade Logic

Cascade Function

Each CY_MUX can be connected to the CY_MUX in the adjacent LC to provide cascadable decode logic. Figure 7 illustrates how the 4-input function generators can be configured to take advantage of these four cascaded CY_MUXes. Note that AND and OR cascading are specific cases of a general decode. In AND cascading all bits are decoded equal to logic one, while in OR cascading all bits are decoded equal to logic zero. The flexibility of the LUT achieves this result. The XC5200 library contains gate macros designed to take advantage of this function.

CLB Flip-Flops and Latches

The CLB can pass the combinatorial output(s) to the interconnect network, but can also store the combinatorial results or other incoming data in flip-flops, and connect their outputs to the interconnect network as well. The CLB storage elements can also be configured as latches.

Table 3: CLB Storage Element Functionality (active rising edge is shown)

Mode	CK	CE	CLR	D	Q
Power-Up or GR	X	X	X	X	0
Flip-Flop	X	X	1	X	0
	__/	1*	0*	D	D
	0	X	0*	X	Q
Latch	1	1*	0*	X	Q
	0	1*	0*	D	D
Both	X	0	0*	X	Q

Legend:

X _	Don't care
__/	Rising edge
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

Data Inputs and Outputs

The source of a storage element data input is programmable. It is driven by the function F, or by the Direct In (DI) block input. The flip-flops or latches drive the Q CLB outputs.

Four fast feed-through paths from DI to DO are available, as shown in Figure 4. This bypass is sometimes used by the automated router to repower internal signals. In addition to the storage element (Q) and direct (DO) outputs, there is a combinatorial output (X) that is always sourced by the Lookup Table.

The four edge-triggered D-type flip-flops or level-sensitive latches have common clock (CK) and clock enable (CE) inputs. Any of the clock inputs can also be permanently enabled. Storage element functionality is described in Table 3.

Clock Input

The flip-flops can be triggered on either the rising or falling clock edge. The clock pin is shared by all four storage elements with individual polarity control. Any inverter placed on the clock input is automatically absorbed into the CLB.

Clock Enable

The clock enable signal (CE) is active High. The CE pin is shared by the four storage elements. If left unconnected for any, the clock enable for that storage element defaults to the active state. CE is not invertible within the CLB.

Clear

An asynchronous storage element input (CLR) can be used to reset all four flip-flops or latches in the CLB. This input

can also be independently disabled for any flip-flop. CLR is active High. It is not invertible within the CLB.

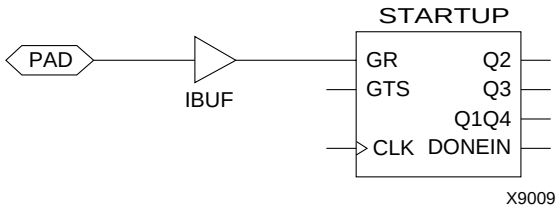

Figure 8: Schematic Symbols for Global Reset

Global Reset

A separate Global Reset line clears each storage element during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GR) does not compete with other routing resources; it uses a dedicated distribution network.

GR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GR pin of the STARTUP symbol. (See Figure 9.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global Reset signal. Alternatively, GR can be driven from any internal node.

Using FPGA Flip-Flops and Latches

The abundance of flip-flops in the XC5200 Series invites pipelined designs. This is a powerful way of increasing performance by breaking the function into smaller subfunctions and executing them in parallel, passing on the results through pipeline flip-flops. This method should be seriously considered wherever throughput is more important than latency.

To include a CLB flip-flop, place the appropriate library symbol. For example, FDCE is a D-type flip-flop with clock enable and asynchronous clear. The corresponding latch symbol is called LDCE.

In XC5200-Series devices, the flip-flops can be used as registers or shift registers without blocking the function generators from performing a different, perhaps unrelated task. This ability increases the functional capacity of the devices.

The CLB setup time is specified between the function generator inputs and the clock input CK. Therefore, the specified CLB flip-flop setup time includes the delay through the function generator.

Three-State Buffers

The XC5200 family has four dedicated Three-State Buffers (TBUFs, or BUFTs in the schematic library) per CLB (see Figure 9). The four buffers are individually configurable through four configuration bits to operate as simple non-inverting buffers or in 3-state mode. When in 3-state mode the CLB output enable (TS) control signal drives the enable to all four buffers. Each TBUF can drive up to two horizontal and/or two vertical Longlines. These 3-state buffers can be used to implement multiplexed or bidirectional buses on the horizontal or vertical longlines, saving logic resources.

The 3-state buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in Table 4.

Table 4: Three-State Buffer Functionality

IN	T	OUT
X	1	Z
IN	0	IN

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array.

The longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver. To ensure the longline goes high when no buffers are on, add an additional BUFT to drive the output High during all of the previously undefined states.

Figure 10 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

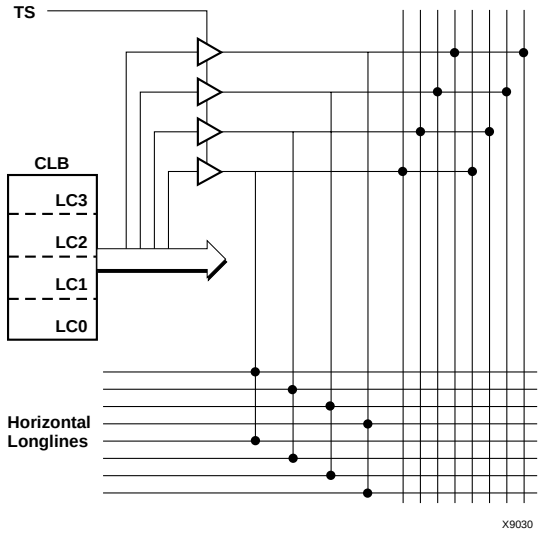

Figure 9: XC5200 3-State Buffers

XC5200-Series devices can also be configured through the boundary scan logic. See XAPP 017 for more information.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-State Control. Non-IOB pins have appropriate partial bit population for In or Out only. PROGRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-State pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions, USER1 and USER2. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).

Instruction Set

The XC5200-Series boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 7.

Table 7: Boundary Scan Instructions

Instruction I2	I1	I0	Test Selected	TDO Source	I/O Data Source
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN.TDO1	User Logic
0	1	1	USER 2	BSCAN.TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	Reserved	—	—
1	1	1	BYPASS	Bypass Register	—

Bit Sequence

The bit sequence within each IOB is: 3-State, Out, In. The data-register cells for the TAP pins TMS, TCK, and TDI have an OR-gate that permanently disables the output buffer if boundary-scan operation is selected. Consequently, it is impossible for the outputs in IOBs used by TAP inputs to conflict with TAP operation. TAP data is taken directly from the pin, and cannot be overwritten by injected boundary-scan data.

The primary global clock inputs (PGCK1-PGCK4) are taken directly from the pins, and cannot be overwritten with boundary-scan data. However, if necessary, it is possible to drive the clock input from boundary scan. The external clock source is 3-stated, and the clock net is driven with boundary scan data through the output driver in the clock-pad IOB. If the clock-pad IOBs are used for non-clock signals, the data may be overwritten normally.

Pull-up and pull-down resistors remain active during boundary scan. Before and during configuration, all pins are pulled up. After configuration, the choice of internal pull-up or pull-down resistor must be taken into account when designing test vectors to detect open-circuit PC traces.

From a cavity-up view of the chip (as shown in XDE or Epic), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Table 8. The device-specific pinout tables for the XC5200 Series include the boundary scan locations for each IOB pin.

Table 8: Boundary Scan Bit Sequence

Bit Position	I/O Pad Location
Bit 0 (TDO)	Top-edge I/O pads (right to left)
Bit 1	...
...	Left-edge I/O pads (top to bottom)
...	Bottom-edge I/O pads (left to right)
...	Right-edge I/O pads (bottom to top)
Bit N (TDI)	BSCANT.UPD

BSDL (Boundary Scan Description Language) files for XC5200-Series devices are available on the Xilinx web site in the File Download area.

Including Boundary Scan

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, include the BSCAN library symbol and connect pad symbols to the TDI, TMS, TCK and TDO pins, as shown in Figure 20.

Table 9: Pin Descriptions (Continued)

Pin Name	I/O During Config.	I/O After Config.	Pin Description
Unrestricted User-Programmable I/O Pins			
I/O	Weak Pull-up	I/O	These pins can be configured to be input and/or output after configuration is completed. Before configuration is completed, these pins have an internal high-value pull-up resistor (20 kΩ - 100 kΩ) that defines the logic level as High.

Configuration

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. XC5200-Series devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Special Purpose Pins

Three configuration mode pins (M2, M1, M0) are sampled prior to configuration to determine the configuration mode. After configuration, these pins can be used as auxiliary I/O connections. The development system does not use these resources unless they are explicitly specified in the design entry. This is done by placing a special pad symbol called MD2, MD1, or MD0 instead of the input or output pad symbol.

In XC5200-Series devices, the mode pins have weak pull-up resistors during configuration. With all three mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the mode pins can be left unconnected. (Note, however, that the internal pull-up resistor value can be as high as 100 kΩ.) After configuration, these pins can individually have weak pull-up or pull-down resistors, as specified in the design. A pull-down resistor value of 3.3kΩ is recommended.

These pins are located in the lower left chip corner and are near the readback nets. This location allows convenient routing if compatibility with the XC2000 and XC3000 family conventions of M0/RT, M1/RD is desired.

Configuration Modes

XC5200 devices have seven configuration modes. These modes are selected by a 3-bit input code applied to the M2, M1, and M0 inputs. There are three self-loading Master modes, two Peripheral modes, and a Serial Slave mode,

Table 10: Configuration Modes

Mode	M2	M1	M0	CCLK	Data
Master Serial	0	0	0	output	Bit-Serial
Slave Serial	1	1	1	input	Bit-Serial
Master Parallel Up	1	0	0	output	Byte-Wide, increment from 00000
Master Parallel Down	1	1	0	output	Byte-Wide, decrement from 3FFFF
Peripheral Synchronous*	0	1	1	input	Byte-Wide
Peripheral Asynchronous	1	0	1	output	Byte-Wide
Express	0	1	0	input	Byte-Wide
Reserved	0	0	1	—	—

Note :*Peripheral Synchronous can be considered byte-wide Slave Parallel

which is used primarily for daisy-chained devices. The seventh mode, called Express mode, is an additional slave mode that allows high-speed parallel configuration. The coding for mode selection is shown in Table 10.

Note that the smallest package, VQ64, only supports the Master Serial, Slave Serial, and Express modes.A detailed description of each configuration mode, with timing information, is included later in this data sheet. During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during configuration are shown in Table 13 on page 124.

Master Modes

The three Master modes use an internal oscillator to generate a Configuration Clock (CCLK) for driving potential slave devices. They also generate address and timing for external PROM(s) containing the configuration data.

Master Parallel (Up or Down) modes generate the CCLK signal and PROM addresses and receive byte parallel data. The data is internally serialized into the FPGA data-frame format. The up and down selection generates starting addresses at either zero or 3FFFF, for compatibility with different microprocessor addressing conventions. The

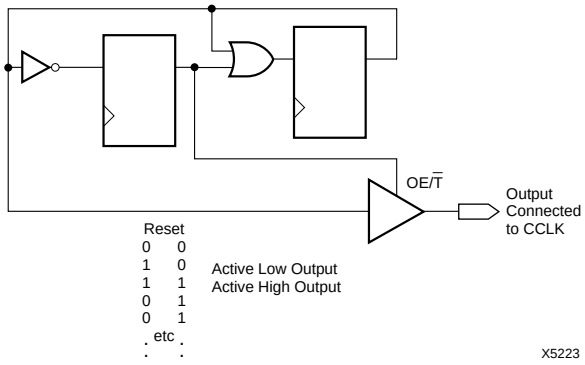

Figure 22: CCLK Generation for XC3000 Master Driving an XC5200-Series Slave

Express Mode

Express mode is similar to Slave Serial mode, except the data is presented in parallel format, and is clocked into the target device a byte at a time rather than a bit at a time. The data is loaded in parallel into eight different columns: it is not internally serialized. Eight bits of configuration data are loaded with every CCLK cycle, therefore this configuration mode runs at eight times the data rate of the other six modes. In this mode the XC5200 family is capable of supporting a CCLK frequency of 10 MHz, which is equivalent to an 80 MHz serial rate, because eight bits of configuration data are being loaded per CCLK cycle. An XC5210 in the Express mode, for instance, can be configured in about 2 ms. The Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

In the Express configuration mode, an external signal drives the CCLK input(s). The first byte of parallel configuration data must be available at the D inputs of the FPGA devices a short set-up time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge. See Figure 38 on page 123.

Bitstream generation currently generates a bitstream sufficient to program in all configuration modes except Express. Extra CCLK cycles are necessary to complete the configuration, since in this mode data is read at a rate of eight bits per CCLK cycle instead of one bit per cycle. Normally the entire start-up sequence requires a number of bits that is equal to the number of CCLK cycles needed. An additional five CCLKs (equivalent to 40 extra bits) will guarantee completion of configuration, regardless of the start-up options chosen.

Multiple slave devices with identical configurations can be wired with parallel D0-D7 inputs. In this way, multiple devices can be configured simultaneously.

Pseudo Daisy Chain

Multiple devices with different configurations can be connected together in a pseudo daisy chain, provided that all of the devices are in Express mode. A single combined bitstream is used to configure the chain of Express mode devices, but the input data bus must drive D0-D7 of each device. Tie High the CS1 pin of the first device to be configured, or leave it floating in the XC5200 since it has an internal pull-up. Connect the DOUT pin of each FPGA to the CS1 pin of the next device in the chain. The D0-D7 inputs are wired to each device in parallel. The DONE pins are wired together, with one or more internal DONE pull-ups activated. Alternatively, a 4.7 kΩ external resistor can be used, if desired. (See Figure 37 on page 122.) CCLK pins are tied together.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All devices in Express mode are synchronized to the DONE pin. User I/O for each device become active after the DONE pin for that device goes High. (The exact timing is determined by options to the bitstream generation software.) Since the DONE pin is open-drain and does not drive a High value, tying the DONE pins of all devices together prevents all devices in the chain from going High until the last device in the chain has completed its configuration cycle.

The status pin DOUT is pulled LOW two internal-oscillator cycles (nominally 1 MHz) after $\overline{\text{INIT}}$ is recognized as High, and remains Low until the device's configuration memory is full. Then DOUT is pulled High to signal the next device in the chain to accept the configuration data on the D7-D0 bus. All devices receive and recognize the six bytes of preamble and length count, irrespective of the level on CS1; but subsequent frame data is accepted only when CS1 is High and the device's configuration memory is not already full.

Setting CCLK Frequency

For Master modes, CCLK can be generated in one of three frequencies. In the default slow mode, the frequency is nominally 1 MHz. In fast CCLK mode, the frequency is nominally 12 MHz. In medium CCLK mode, the frequency is nominally 6 MHz. The frequency range is -50% to +50%. The frequency is selected by an option when running the bitstream generation software. If an XC5200-Series Master is driving an XC3000- or XC2000-family slave, slow CCLK mode must be used. Slow mode is the default.

Table 11: XC5200 Bitstream Format

Data Type	Value	Occurrences
Fill Byte	11111111	Once per bitstream
Preamble	11110010	
Length Counter	COUNT(23:0)	
Fill Byte	11111111	

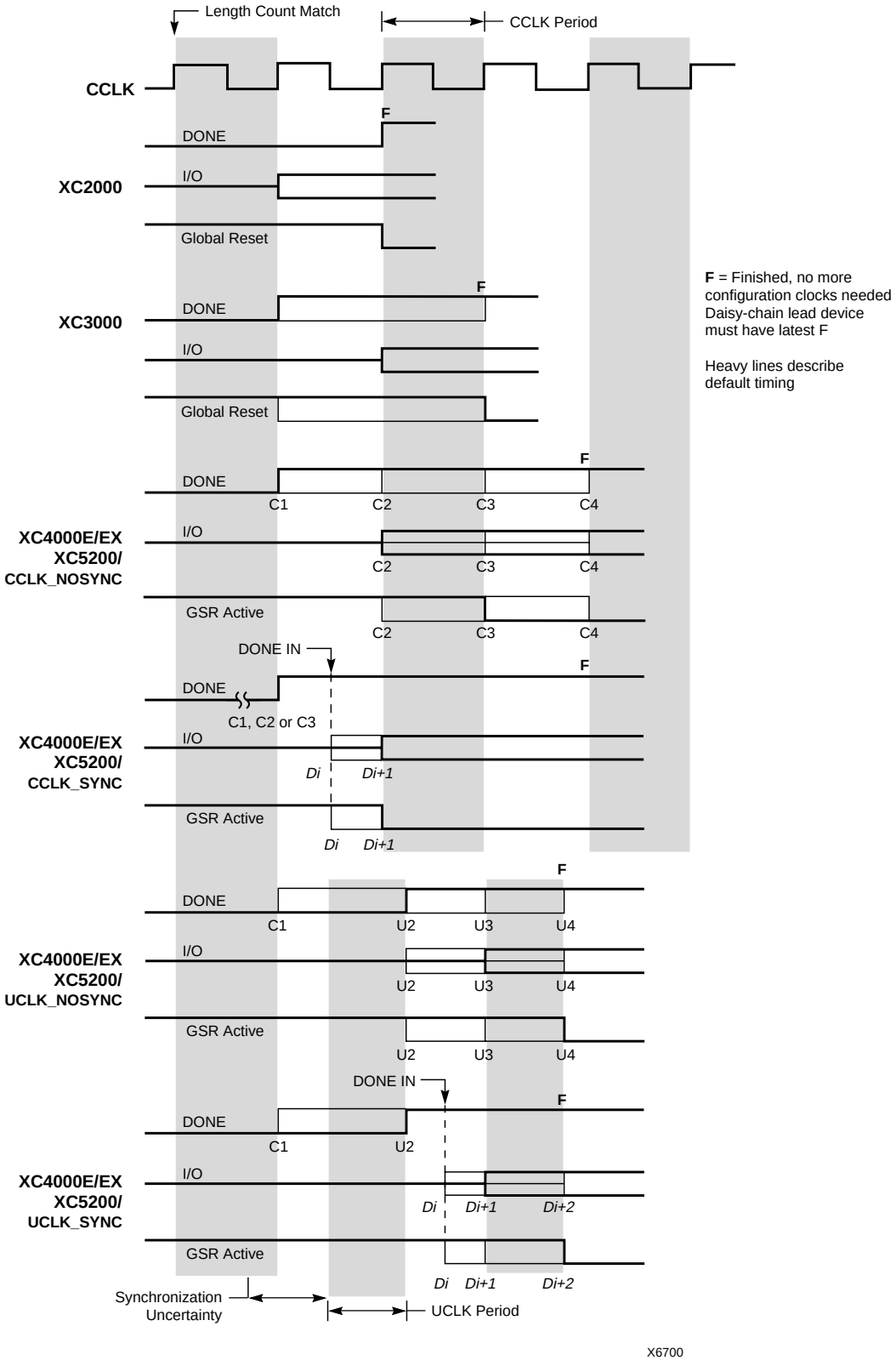

Figure 25: Start-up Timing

DONE High to active user I/O is controlled by an option to the bitstream generation software.

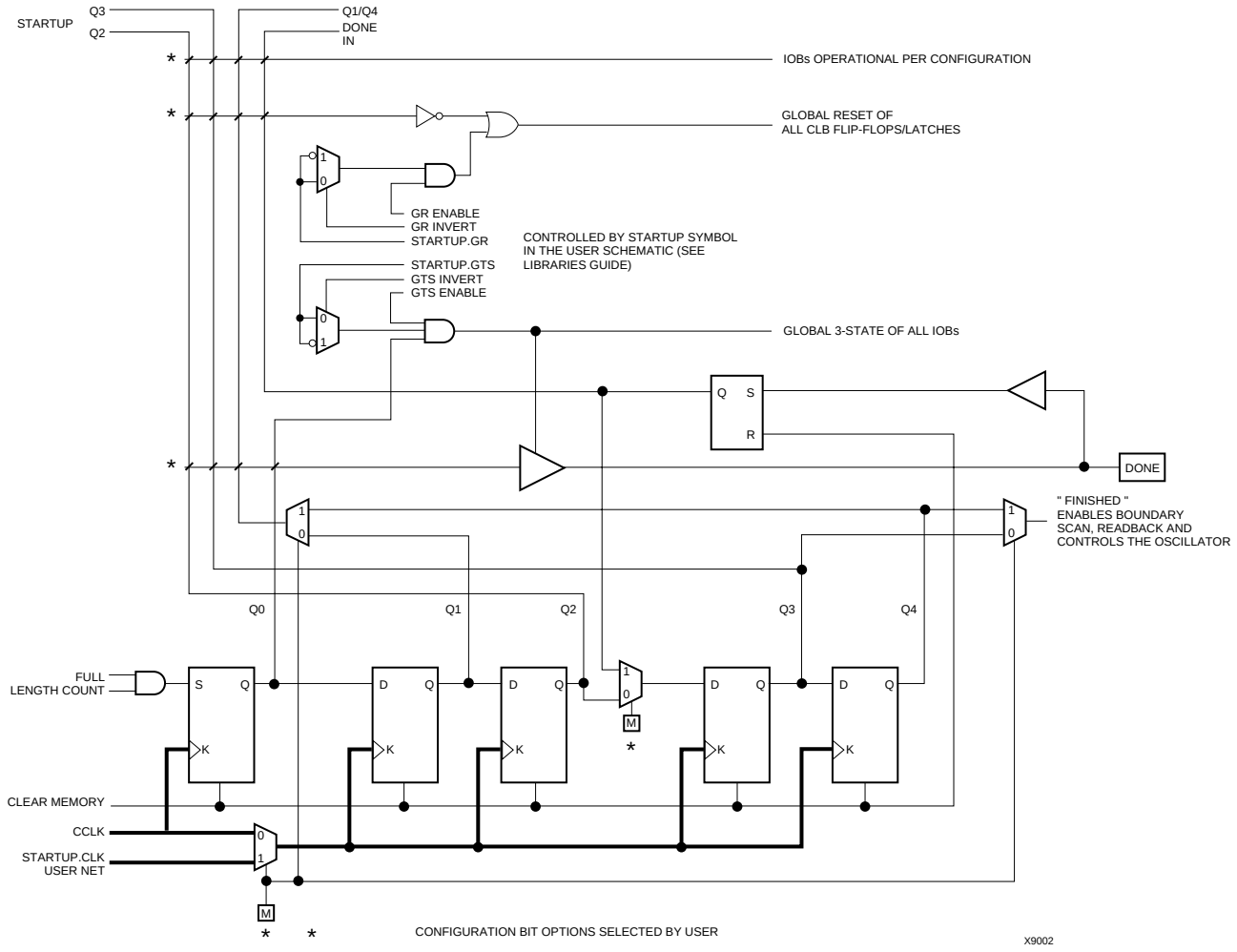

Figure 26: Start-up Logic

Release of Global Reset After DONE Goes High

By default, Global Reset (GR) is released two CCLK cycles after the DONE pin goes High. If CCLK is not clocked twice after DONE goes High, all flip-flops are held in their initial reset state. The delay from DONE High to GR inactive is controlled by an option to the bitstream generation software.

Configuration Complete After DONE Goes High

Three full CCLK cycles are required after the DONE pin goes High, as shown in Figure 25 on page 109. If CCLK is not clocked three times after DONE goes High, readback cannot be initiated and most boundary scan instructions cannot be used.

Configuration Through the Boundary Scan Pins

XC5200-Series devices can be configured through the boundary scan pins.

For detailed information, refer to the Xilinx application note XAPP017, "*Boundary Scan in XC4000 and XC5200 Devices*."

Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs.

XC5200 Global Buffer Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

		Speed Grade	-6	-5	-4	-3
Description	**Symbol**	**Device**	**Max (ns)**	**Max (ns)**	**Max (ns)**	**Max (ns)**
Global Signal Distribution	T_{BUFG}	XC5202	9.1	8.5	8.0	6.9
From pad through global buffer, to any clock (CK)		XC5204	9.3	8.7	8.2	7.6
		XC5206	9.4	8.8	8.3	7.7
		XC5210	9.4	8.8	8.5	7.7
		XC5215	10.5	9.9	9.8	9.6

XC5200 Longline Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

		Speed Grade	-6	-5	-4	-3
Description	**Symbol**	**Device**	**Max (ns)**	**Max (ns)**	**Max (ns)**	**Max (ns)**
TBUF driving a Longline TS I — O TBUF I to Longline, while TS is Low; i.e., buffer is constantly active	T_{IO}	XC5202	6.0	3.8	3.0	2.0
		XC5204	6.4	4.1	3.2	2.3
		XC5206	6.6	4.2	3.3	2.7
		XC5210	6.6	4.2	3.3	2.9
		XC5215	7.3	4.6	3.8	3.2
TS going Low to Longline going from floating High or Low to active Low or High	T_{ON}	XC5202	7.8	5.6	4.7	4.0
		XC5204	8.3	5.9	4.9	4.3
		XC5206	8.4	6.0	5.0	4.4
		XC5210	8.4	6.0	5.0	4.4
		XC5215	8.9	6.3	5.3	4.5
TS going High to TBUF going inactive, not driving Longline	T_{OFF}	XC52xx	3.0	2.8	2.6	2.4

Note: 1. Die-size-dependent parameters are based upon XC5215 characterization. Production specifications will vary with array size.

XC5200 CLB Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

Speed Grade		-6		-5		-4		-3	
Description	**Symbol**	**Min (ns)**	**Max (ns)**	**Min (ns)**	**Max (ns)**	**Min (ns)**	**Max (ns)**	**Min (ns)**	**Max (ns)**
Combinatorial Delays									
F inputs to X output	T_{ILO}		5.6		4.6		3.8		3.0
F inputs via transparent latch to Q	T_{ITO}		8.0		6.6		5.4		4.3
DI inputs to DO output (Logic-Cell Feedthrough)	T_{IDO}		4.3		3.5		2.8		2.4
F inputs via F5_MUX to DO output	T_{IMO}		7.2		5.8		5.0		4.3
Carry Delays									
Incremental delay per bit	T_{CY}		0.7		0.6		0.5		0.5
Carry-in overhead from DI	T_{CYDI}		1.8		1.6		1.5		1.4
Carry-in overhead from F	T_{CYL}		3.7		3.2		2.9		2.4
Carry-out overhead to DO	T_{CYO}		4.0		3.2		2.5		2.1
Sequential Delays									
Clock (CK) to out (Q) (Flip-Flop)	T_{CKO}		5.8		4.9		4.0		4.0
Gate (Latch enable) going active to out (Q)	T_{GO}		9.2		7.4		5.9		5.5
Set-up Time Before Clock (CK)									
F inputs	T_{ICK}	2.3		1.8		1.4		1.3	
F inputs via F5_MUX	T_{MICK}	3.8		3.0		2.5		2.4	
DI input	T_{DICK}	0.8		0.5		0.4		0.4	
CE input	T_{EICK}	1.6		1.2		0.9		0.9	
Hold Times After Clock (CK)									
F inputs	T_{CKI}	0		0		0		0	
F inputs via F5_MUX	T_{CKMI}	0		0		0		0	
DI input	T_{CKDI}	0		0		0		0	
CE input	T_{CKEI}	0		0		0		0	
Clock Widths									
Clock High Time	T_{CH}	6.0		6.0		6.0		6.0	
Clock Low Time	T_{CL}	6.0		6.0		6.0		6.0	
Toggle Frequency (MHz) (Note 3)	F_{TOG}		83		83		83		83
Reset Delays									
Width (High)	T_{CLRW}	6.0		6.0		6.0		6.0	
Delay from CLR to Q (Flip-Flop)	T_{CLR}		7.7		6.3		5.1		4.0
Delay from CLR to Q (Latch)	T_{CLRL}		6.5		5.2		4.2		3.0
Global Reset Delays									
Width (High)	T_{GCLRW}	6.0		6.0		6.0		6.0	
Delay from internal GR to Q	T_{GCLR}		14.7		12.1		9.1		8.0

Note:
1. The CLB K to Q output delay (T_{CKO}) of any CLB, plus the shortest possible interconnect delay, is always longer than the Data In hold-time requirement (T_{CKDI}) of any CLB on the same die.
2. Timing is based upon the XC5215 device. For other devices, see Timing Calculator.
3. Maximum flip-flop toggle rate for export control purposes.

XC5200 IOB Switching Characteristic Guidelines

Testing of the switching parameters is modeled after testing methods specified by MIL-M-38510/605. All devices are 100% functionally tested. Since many internal timing parameters cannot be measured directly, they are derived from benchmark timing patterns. The following guidelines reflect worst-case values over the recommended operating conditions. For more detailed, more precise, and more up-to-date timing information, use the values provided by the timing calculator and used in the simulator.

Speed Grade		-6	-5	-4	-3
Description	**Symbol**	**Max (ns)**	**Max (ns)**	**Max (ns)**	**Max (ns)**
Input					
Propagation Delays from CMOS or TTL Levels					
Pad to I (no delay)	T_{PI}	5.7	5.0	4.8	3.3
Pad to I (with delay)	T_{PID}	11.4	10.2	10.2	9.5
Output					
Propagation Delays to CMOS or TTL Levels					
Output (O) to Pad (fast)	T_{OPF}	4.6	4.5	4.5	3.5
Output (O) to Pad (slew-limited)	T_{OPS}	9.5	8.4	8.0	5.0
From clock (CK) to output pad (fast), using direct connect between Q and output (O)	T_{OKPOF}	10.1	9.3	8.3	7.5
From clock (CK) to output pad (slew-limited), using direct connect between Q and output (O)	T_{OKPOS}	14.9	13.1	11.8	10.0
3-state to Pad active (fast)	T_{TSONF}	5.6	5.2	4.9	4.6
3-state to Pad active (slew-limited)	T_{TSONS}	10.4	9.0	8.3	6.0
Internal GTS to Pad active	T_{GTS}	17.7	15.9	14.7	13.5

Note:
1. Timing is measured at pin threshold, with 50-pF external capacitance loads. **Slew-limited** output rise/fall times are approximately two times longer than **fast** output rise/fall times.
2. Unused and unbonded IOBs are configured by default as inputs with internal pull-up resistors.
3. Timing is based upon the XC5215 device. For other devices, see Timing Calculator.

XC5200 Boundary Scan (JTAG) Switching Characteristic Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions. They are expressed in units of nanoseconds and apply to all XC5200 devices unless otherwise noted.

Speed Grade		-6		-5		-4		-3	
Description	**Symbol**	**Min**	**Max**	**Min**	**Max**	**Min**	**Max**	**Min**	**Max**
Setup and Hold									
Input (TDI) to clock (TCK) setup time	T_{TDITCK}	30.0		30.0		30.0		30.0	
Input (TDI) to clock (TCK) hold time	T_{TCKTDI}	0		0		0		0	
Input (TMS) to clock (TCK) setup time	T_{TMSTCK}	15.0		15.0		15.0		15.0	
Input (TMS) to clock (TCK) hold time	T_{TCKTMS}	0		0		0		0	
Propagation Delay									
Clock (TCK) to Pad (TDO)	T_{TCKPO}		30.0		30.0		30.0		30.0
Clock									
Clock (TCK) High	T_{TCKH}	30.0		30.0		30.0		30.0	
Clock (TCK) Low	T_{TCKL}	30.0		30.0		30.0		30.0	
F_{MAX} (MHz)	F_{MAX}		10.0		10.0		10.0		10.0

Note 1: Input pad setup and hold times are specified with respect to the internal clock.

Device-Specific Pinout Tables

Device-specific tables include all packages for each XC5200-Series device. They follow the pad locations around the die, and include boundary scan register locations.

Pin Locations for XC5202 Devices

The following table may contain pinout information for unsupported device/package combinations. Please see the availability charts elsewhere in the XC5200 Series data sheet for availability information.

Pin	Description	VQ64*	PC84	PQ100	VQ100	TQ144	PG156	Boundary Scan Order
	VCC	-	2	92	89	128	H3	-
1.	I/O (A8)	57	3	93	90	129	H1	51
2.	I/O (A9)	58	4	94	91	130	G1	54
3.	I/O	-	-	95	92	131	G2	57
4.	I/O	-	-	96	93	132	G3	63
5.	I/O (A10)	-	5	97	94	133	F1	66
6.	I/O (A11)	59	6	98	95	134	F2	69
	GND	-	-	-	-	137	F3	-
7.	I/O (A12)	60	7	99	96	138	E3	78
8.	I/O (A13)	61	8	100	97	139	C1	81
9.	I/O (A14)	62	9	1	98	142	B1	90
10.	I/O (A15)	63	10	2	99	143	B2	93
	VCC	64	11	3	100	144	C3	-
	GND	-	12	4	1	1	C4	-
11.	GCK1 (A16, I/O)	1	13	5	2	2	B3	102
12.	I/O (A17)	2	14	6	3	3	A1	105
13.	I/O (TDI)	3	15	7	4	6	B4	111
14.	I/O (TCK)	4	16	8	5	7	A3	114
	GND	-	-	-	-	8	C6	-
15.	I/O (TMS)	5	17	9	6	11	A5	117
16.	I/O	6	18	10	7	12	C7	123
17.	I/O	-	-	-	-	13	B7	126
18.	I/O	-	-	11	8	14	A6	129
19.	I/O	-	19	12	9	15	A7	135
20.	I/O	7	20	13	10	16	A8	138
	GND	8	21	14	11	17	C8	-
	VCC	9	22	15	12	18	B8	-
21.	I/O	-	23	16	13	19	C9	141
22.	I/O	10	24	17	14	20	B9	147
23.	I/O		-	18	15	21	A9	150
24.	I/O		-	-	-	22	B10	153
25.	I/O	-	25	19	16	23	C10	159
26.	I/O	11	26	20	17	24	A10	162
	GND		-	-	-	27	C11	-
27.	I/O	12	27	21	18	28	B12	165
28.	I/O		-	22	19	29	A13	171
29.	I/O	13	28	23	20	32	B13	174
30.	I/O	14	29	24	21	33	B14	177
31.	M1 (I/O)	15	30	25	22	34	A15	186
	GND	-	31	26	23	35	C13	-
32.	M0 (I/O)	16	32	27	24	36	A16	189
	VCC	-	33	28	25	37	C14	-
33.	M2 (I/O)	17	34	29	26	38	B15	192
34.	GCK2 (I/O)	18	35	30	27	39	B16	195

Pin	Description		PC84	PQ100	VQ100	TQ144	PG156	PQ160	Boundary Scan Order
57.	I/O		-	-	-	47	E16	53	306
58.	I/O		38	34	31	48	F16	54	312
59.	I/O		39	35	32	49	G14	55	315
60.	I/O		-	36	33	50	G15	56	318
61.	I/O		-	37	34	51	G16	57	324
62.	I/O		40	38	35	52	H16	58	327
63.	I/O ($\overline{ERR}$, $\overline{INIT}$)		41	39	36	53	H15	59	330
	VCC		42	40	37	54	H14	60	-
	GND		43	41	38	55	J14	61	-
64.	I/O		44	42	39	56	J15	62	336
65.	I/O		45	43	40	57	J16	63	339
66.	I/O		-	44	41	58	K16	64	348
67.	I/O		-	45	42	59	K15	65	351
68.	I/O		46	46	43	60	K14	66	354
69.	I/O		47	47	44	61	L16	67	360
70.	I/O		-	-	-	62	M16	68	363
71.	I/O		-	-	-	63	L15	69	366
	GND		-	-	-	64	L14	70	-
72.	I/O		-	-	-	-	N16	71	372
73.	I/O		-	-	-	-	M15	72	375
74.	I/O		48	48	45	65	P16	73	378
75.	I/O		49	49	46	66	M14	74	384
76.	I/O		-	-	-	67	N15	75	387
77.	I/O		-	-	-	68	P15	76	390
78.	I/O		50	50	47	69	N14	77	396
79.	I/O		51	51	48	70	R16	78	399
	GND		52	52	49	71	P14	79	-
	DONE		53	53	50	72	R15	80	-
	VCC		54	54	51	73	P13	81	-
	PROG		55	55	52	74	R14	82	-
80.	I/O (D7)		56	56	53	75	T16	83	408
81.	GCK3 (I/O)		57	57	54	76	T15	84	411
82.	I/O		-	-	-	77	R13	85	420
83.	I/O		-	-	-	78	P12	86	423
84.	I/O (D6)		58	58	55	79	T14	87	426
85.	I/O		-	59	56	80	T13	88	432
	GND		-	-	-	81	P11	91	-
86.	I/O		-	-	-	82	R11	92	435
87.	I/O		-	-	-	83	T11	93	438
88.	I/O (D5)		59	60	57	84	T10	94	444
89.	I/O ($\overline{CS0}$)		60	61	58	85	P10	95	447
90.	I/O		-	62	59	86	R10	96	450
91.	I/O		-	63	60	87	T9	97	456
92.	I/O (D4)		61	64	61	88	R9	98	459
93.	I/O		62	65	62	89	P9	99	462
	VCC		63	66	63	90	R8	100	-
	GND		64	67	64	91	P8	101	-
94.	I/O (D3)		65	68	65	92	T8	102	468
95.	I/O ($\overline{RS}$)		66	69	66	93	T7	103	471
96.	I/O		-	70	67	94	T6	104	474
97.	I/O		-	-	-	95	R7	105	480
98.	I/O (D2)		67	71	68	96	P7	106	483

Pin	Description	PC84	PQ100	VQ100	TQ144	PQ160	TQ176	PG191	PQ208	Boundary Scan Order
	CCLK	73	77	74	107	119	131	V1	153	-
	VCC	74	78	75	108	120	132	R4	154	-
130.	I/O (TDO)	75	79	76	109	121	133	U2	159	-
	GND	76	80	77	110	122	134	R3	160	-
131.	I/O (A0, $\overline{WS}$)	77	81	78	111	123	135	T3	161	9
132.	GCK4 (A1, I/O)	78	82	79	112	124	136	U1	162	15
133.	I/O	-	-	-	113	125	137	P3	163	18
134.	I/O	-	-	-	114	126	138	R2	164	21
135.	I/O (A2, CS1)	79	83	80	115	127	139	T2	165	27
136.	I/O (A3)	80	84	81	116	128	140	N3	166	30
137.	I/O	-	-	-	117	129	141	P2	167	33
138.	I/O	-	-	-	-	130	142	T1	168	42
	GND	-	-	-	118	131	143	M3	171	-
139.	I/O	-	-	-	119	132	144	P1	172	45
140.	I/O	-	-	-	120	133	145	N1	173	51
141.	I/O (A4)	81	85	82	121	134	146	M2	174	54
142.	I/O (A5)	82	86	83	122	135	147	M1	175	57
143.	I/O	-	-	-	-	-	148	L3	176	63
144.	I/O	-	-	-	-	136	149	L2	177	66
145.	I/O	-	87	84	123	137	150	L1	178	69
146.	I/O	-	88	85	124	138	151	K1	179	75
147.	I/O (A6)	83	89	86	125	139	152	K2	180	78
148.	I/O (A7)	84	90	87	126	140	153	K3	181	81
	GND	1	91	88	127	141	154	K4	182	-

Additional No Connect (N.C.) Connections for PQ208 and TQ176 Packages

PQ208							TQ176
195	1	39	65	104	143	158	167
196	3	51	66	105	144	169	
206	12	52	91	107	155	170	
207	13	53	92	117	156		
208	38	54	102	118	157		

Notes: Boundary Scan Bit 0 = TDO.T
Boundary Scan Bit 1 = TDO.O
Boundary Scan Bit 1056 = BSCAN.UPD

Pin Locations for XC5210 Devices

The following table may contain pinout information for unsupported device/package combinations. Please see the availability charts elsewhere in the XC5200 Series data sheet for availability information.

Pin	Description	PC84	TQ144	PQ160	TQ176	PQ208	PG223	BG225	PQ240	Boundary Scan Order
	VCC	2	128	142	155	183	J4	VCC*	212	-
1.	I/O (A8)	3	129	143	156	184	J3	E8	213	111
2.	I/O (A9)	4	130	144	157	185	J2	B7	214	114
3.	I/O	-	131	145	158	186	J1	A7	215	117
4.	I/O	-	132	146	159	187	H1	C7	216	123
5.	I/O	-	-	-	160	188	H2	D7	217	126
6.	I/O	-	-	-	161	189	H3	E7	218	129

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
100.	I/O	-	-	-	F17	-	AE22	558
101.	I/O	-	-	-	G16	-	AF23	564
102.	I/O	49	63	69	D19	K7	AD20	567
103.	I/O	50	64	70	E18	M5	AE21	570
104.	I/O	-	65	71	D20	R4	AF21	576
105.	I/O	-	66	72	G17	N5	AC19	579
106.	I/O	-	-	73	F18	P5	AD19	582
107.	I/O	-	-	74	H16	L6	AE20	588
108.	I/O	-	-	-	E19	-	AF20	591
109.	I/O	-	-	-	F19	-	AC18	594
	GND	51	67	75	E20	GND*	GND*	-
110.	I/O	52	68	76	H17	R5	AD18	600
111.	I/O	53	69	77	G18	M6	AE19	603
112.	I/O	54	70	78	G19	N6	AC17	606
113.	I/O	55	71	79	H18	P6	AD17	612
	VCC	-	-	80	F20	VCC*	VCC*	-
114.	I/O	-	72	81	J16	R6	AE17	615
115.	I/O	-	73	82	G20	M7	AE16	618
116.	I/O	-	-	-	H20	-	AF16	624
117.	I/O	-	-	-	J18	-	AC15	627
118.	I/O	-	-	84	J19	N7	AD15	630
119.	I/O	-	-	85	K16	P7	AE15	636
120.	I/O	56	74	86	J20	R7	AF15	639
121.	I/O	57	75	87	K17	L7	AD14	642
122.	I/O	58	76	88	K18	N8	AE14	648
123.	I/O ($\overline{\text{ERR}}$, $\overline{\text{INIT}}$)	59	77	89	K19	P8	AF14	651
	VCC	60	78	90	L20	VCC*	VCC*	-
	GND	61	79	91	K20	GND*	GND*	-
124.	I/O	62	80	92	L19	L8	AE13	660
125.	I/O	63	81	93	L18	P9	AC13	663
126.	I/O	64	82	94	L16	R9	AD13	672
127.	I/O	65	83	95	L17	N9	AF12	675
128.	I/O	-	84	96	M20	M9	AE12	678
129.	I/O	-	85	97	M19	L9	AD12	684
130.	I/O	-	-	-	N20	-	AC12	687
131.	I/O	-	-	-	M18	-	AF11	690
132.	I/O	-	-	99	N19	R10	AE11	696
133.	I/O	-	-	100	P20	P10	AD11	699
	VCC	-	-	101	T20	VCC*	VCC*	-
134.	I/O	66	86	102	N18	N10	AE9	702
135.	I/O	67	87	103	P19	K9	AD9	708
136.	I/O	68	88	104	N17	R11	AC10	711
137.	I/O	69	89	105	R19	P11	AF7	714
	GND	70	90	106	R20	GND*	GND*	-
138.	I/O	-	-	-	N16	-	AE8	720
139.	I/O	-	-	-	P18	-	AD8	723
140.	I/O	-	-	107	U20	M10	AC9	726
141.	I/O	-	-	108	P17	N11	AF6	732
142.	I/O	-	91	109	T19	R12	AE7	735
143.	I/O	-	92	110	R18	L10	AD7	738
144.	I/O	71	93	111	P16	P12	AE6	744
145.	I/O	72	94	112	V20	M11	AE5	747

Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
190.	I/O	-	-	-	X8	-	M4	951
191.	I/O	-	-	-	V9	-	L1	954
192.	I/O (D2)	106	138	159	W8	G11	J1	960
193.	I/O	107	139	160	X7	F15	K3	963
	VCC	-	-	161	X5	VCC*	VCC*	
194.	I/O	108	140	162	V8	F14	J2	966
195.	I/O	109	141	163	W7	F13	J3	972
196.	I/O	-	-	164	U8	G10	K4	975
197.	I/O	-	-	165	W6	E15	G1	978
	GND	110	142	166	X6	GND*	GND*	
198.	I/O	-	-	-	T8	-	H2	984
199.	I/O	-	-	-	V7	-	H3	987
200.	I/O	-	-	167	X4	E14	J4	990
201.	I/O	-	-	168	U7	F12	F1	996
202.	I/O	-	143	169	W5	E13	G2	999
203.	I/O	-	144	170	V6	D15	G3	1002
204.	I/O	111	145	171	T7	F11	F2	1008
205.	I/O	112	146	172	X3	D14	E2	1011
206.	I/O (D1)	113	147	173	U6	E12	F3	1014
207.	I/O ($\overline{\text{RCLK-BUSY}}$/RDY)	114	148	174	V5	C15	G4	1020
208.	I/O	-	-	-	W4	-	D2	1023
209.	I/O	-	-	-	W3	-	F4	1032
210.	I/O	115	149	175	T6	D13	E3	1035
211.	I/O	116	150	176	U5	C14	C2	1038
212.	I/O (D0, DIN)	117	151	177	V4	F10	D3	1044
213.	I/O (DOUT)	118	152	178	X1	B15	E4	1047
	CCLK	119	153	179	V3	C13	C3	-
	VCC	120	154	180	W1	VCC*	VCC*	-
214.	I/O (TDO)	121	159	181	U4	A15	D4	0
	GND	122	160	182	X2	GND*	GND*	-
215.	I/O (A0, $\overline{\text{WS}}$)	123	161	183	W2	A14	B3	9
216.	GCK4 (A1, I/O)	124	162	184	V2	B13	C4	15
217.	I/O	125	163	185	R5	E11	D5	18
218.	I/O	126	164	186	T4	C12	A3	21
219.	I/O (A2, CS1)	127	165	187	U3	A13	D6	27
220.	I/O (A3)	128	166	188	V1	B12	C6	30
221.	I/O	-	-	-	R4	-	B5	33
222.	I/O	-	-	-	P5	-	A4	39
223.	I/O	-	-	189	U2	F9	C7	42
224.	I/O	-	-	190	T3	D11	B6	45
225.	I/O	129	167	191	U1	A12	A6	51
226.	I/O	130	168	192	P4	C11	D8	54
227.	I/O	-	169	193	R3	B11	B7	57
228.	I/O	-	170	194	N5	E10	A7	63
229.	I/O	-	-	195	T2	-	D9	66
230.	I/O	-	-	-	R2	-	C9	69
	GND	131	171	196	T1	GND*	GND*	-
231.	I/O	132	172	197	N4	A11	B8	75
232.	I/O	133	173	198	P3	D10	D10	78
233.	I/O	-	-	199	P2	C10	C10	81
234.	I/O	-	-	200	N3	B10	B9	87
	VCC	-	-	201	R1	VCC*	VCC*	-

Revisions

Version	Description
12/97	Rev 5.0 added -3, -4 specification
7/98	Rev 5.1 added Spartan family to comparison, removed HQ304
11/98	Rev 5.2 All specifications made final.